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STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 11

of 12

Application Number	10/804,926
Filing Date	03/19/04
First Named Inventor	Khazeni, K.
Art Unit	2877
Examiner Name	Unknown
Attorney Docket Number	HDI-103

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number <small>Number-Kind Code² # Issues</small>	Publication Date <small>MM-DD-YYYY</small>	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
MD	A	US- 6,515,745 B2	02/04/2003	Vurens et al.	See Statement
	B	US- 6,307,627 B1	10/23/2001	Vurens	See Statement
	C	US- 6,134,011	10/17/2000	Kilen et al.	See Statement
	D	US- 5,835,220	11/10/1998	Kazama et al.	See Statement
	E	US- 5,790,259	08/04/1998	Mizuhata et al.	See Statement
	F	US- 5,726,455	03/10/1998	Vurens	See Statement
	G	US- 5,644,562	07/01/1997	De Groot	See Statement
	H	US- 5,438,415	08/01/1995	Kazama et al.	See Statement
	J	US- 5,335,068	08/02/1994	Yamada et al.	See Statement
	K	US- 5,311,285	05/10/1994	Oshige et al.	See Statement
	L	US- 5,282,217	01/25/1994	Yamazaki	See Statement
	M	US- 5,102,222	04/07/1992	Berger et al.	See Statement
	N	US- 4,908,508	03/13/1990	Dubbeldam	See Statement
	O	US- 4,893,932	01/16/1990	Knollenberg	See Statement
	P	US- 4,872,758	10/10/1989	Miyazaki et al.	See Statement
	Q	US- 4,681,450	07/21/1987	Azzam	See Statement
	R	US- 4,585,348	04/29/1986	Chastang et al.	See Statement
MD	S	US- 5,517,312	05/14/1996	Fikarov	See Statement
		US-			

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document <small>Country Code³ "Number" "Kind Code⁴ (# known)</small>	Publication Date <small>MM-DD-YYYY</small>	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
					T ⁵

Examiner Signature	/Marissa Detschel/	Date Considered	02/08/2007
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(Use as many sheets as necessary)

Sheet

2

of

2

Application Number	10/804,926
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First Named Inventor	Khazeni, K.
Art Unit	2877
Examiner Name	Unknown
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
MD	T	AZZAM R.M.A. "Ellipsometry" Handbook of Optics: Devices, Measurements & Properties Vol II, 2nd Edition, Bass, M. et al.(eds).	
		McGraw Hill, Inc.: Chapter 27, pp. 27-1 - 27.26 (1995)	
MD	U	MEEKS, S. et al. "Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks" Transactions of the ASME, presented Oct 1994, Maui, HI	
MD	V	BRIGHT, D. et al. "Concentration histogram imaging: a quantitative view of related images" Microscopy: The Key Research Tool, March 1992 pp. 21-28	
MD	W	KLEIN, D. et al. "Measurements of Thin Film Disks by Surface Reflectance Analysis" SPIE Conference on Surface Characterization for Computer Disks,	
		Wafers and Flat Panel Displays, San Jose, CA January 1999, Volume 3619, pp. 18 - 26	
MD	X	Optics, MILES V. KLEIN and THOMAS E. FURTAK, Second Edition, Wiley, pp. 134 - 135 (1986)	

Examiner Signature	/Marissa Detschel/	Date Considered	02/08/2007
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¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Not for submission under 37 CFR 1.99)</i>	Application Number		10804926
	Filing Date		2004-03-19
	First Named Inventor		Kasra Khazeni
	Art Unit		2877
	Examiner Name		Detschel, Marissa
	Attorney Docket Number		KLAP1679US

MD	1	MILES V. KLEIN and THOMAS E. FURTAK, Optics & Laser Physics, Second Edition , April, 1986, pages 134-135, Wiley	<input type="checkbox"/>
MD	2	MICHAEL BASS, Handbook of Optics, Second Edition, Volume II, 1995, pages 27.1, 27.15-17, 27.25, and 27.26 , McGraw Hill, Inc.	<input type="checkbox"/>
MD	3	DAVID L. KLEIN, GERARD H. VURENS, Measurements of Thin Film Disks by Surface Reflectance Analysis, Surface Characterization for Computer Disks, Wafers, and Flat Panel Displays, January 28, 1999, pages 18-26, Volume 3619, The Society of Photo-Optical Instrumentation Engineers, San Jose, California, USA	<input type="checkbox"/>

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